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# Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	9216
Total RAM Bits	55296
Number of I/O	178
Number of Gates	400000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	256-LBGA
Supplier Device Package	256-FPBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/agl400v2-fgg256t

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Ramping up (V2 devices):  $0.65 \text{ V} < \text{trip\_point\_up} < 1.05 \text{ V}$ Ramping down (V2 devices):  $0.55 \text{ V} < \text{trip\_point\_down} < 0.95 \text{ V}$ 

VCC and VCCI ramp-up trip points are about 100 mV higher than ramp-down trip points. This specifically built-in hysteresis prevents undesirable power-up oscillations and current surges. Note the following:

- During programming, I/Os become tristated and weakly pulled up to VCCI.
- JTAG supply, PLL power supplies, and charge pump VPUMP supply have no influence on I/O behavior.

### PLL Behavior at Brownout Condition

Microsemi recommends using monotonic power supplies or voltage regulators to ensure proper power-up behavior. Power ramp-up should be monotonic at least until VCC and VCCPLX exceed brownout activation levels (see Figure 2-1 and Figure 2-2 on page 2-5 for more details).

When PLL power supply voltage and/or VCC levels drop below the VCC brownout levels (0.75 V  $\pm$  0.25 V for V5 devices, and 0.75 V  $\pm$  0.2 V for V2 devices), the PLL output lock signal goes low and/or the output clock is lost. Refer to the Brownout Voltage section in the "Power-Up/-Down Behavior of Low Power Flash Devices" chapter of the *ProASIC®* and *ProASIC3E* FPGA fabric user guides for information on clock and lock recovery.

## Internal Power-Up Activation Sequence

- 1. Core
- 2. Input buffers
- 3. Output buffers, after 200 ns delay from input buffer activation

To make sure the transition from input buffers to output buffers is clean, ensure that there is no path longer than 100 ns from input buffer to output buffer in your design.

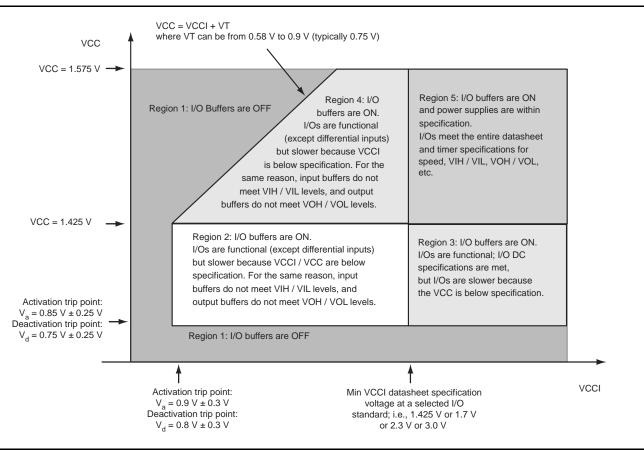


Figure 2-1 • V5 Devices – I/O State as a Function of VCCI and VCC Voltage Levels

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Table 2-20 • Different Components Contributing to the Static Power Consumption in IGLOO Devices For IGLOO V2 or V5 Devices, 1.5 V DC Core Supply Voltage

			Device-Specific Static Power (mW)						
Parameter	Definition	AGL1000	AGL600	AGL400	AGL250	AGL125	AGL060	AGL030	AGL015
PDC1	Array static power in Active mode		See Table 2-12 on page 2-9.						
PDC2	Array static power in Static (Idle) mode		See Table 2-11 on page 2-8.						
PDC3	Array static power in Flash*Freeze mode		See Table 2-9 on page 2-7.						
PDC4	Static PLL contribution				1.8	34			
PDC5	Bank quiescent power (V <sub>CCI</sub> -dependent)			See	Table 2-12	2 on page 2	2-9.		
PDC6	I/O input pin static power (standard-dependent)	See Table 2-13 on page 2-10 through Table 2-15 on page 2-11.							
PDC7	I/O output pin static power (standard-dependent)		See Table 2-16 on page 2-11 through Table 2-18 on page 2-12.						

Note: \*For a different output load, drive strength, or slew rate, Microsemi recommends using the Microsemi power spreadsheet calculator or SmartPower tool in Libero SoC.

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Table 2-97 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard I/O Banks

1.8 V LVCMOS		VIL	VIH		VOL	VOH	IOL	ЮН	IOSH	IOSL	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μ <b>Α</b> <sup>4</sup>
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI - 0.45	2	2	9	11	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI - 0.45	4	4	17	22	10	10

#### Notes:

- 1. IIL is the input leakage current per I/O pin over recommended operation conditions where -0.3 V < VIN < VIL.
- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges
- 3. Currents are measured at 100°C junction temperature and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.

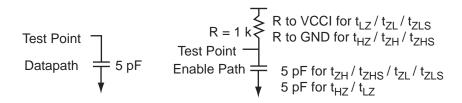


Figure 2-9 • AC Loading

Table 2-98 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	C <sub>LOAD</sub> (pF)
0	1.8	0.9	5

Note: \*Measuring point = Vtrip. See Table 2-29 on page 2-28 for a complete table of trip points.

### **Timing Characteristics**

### 1.5 V DC Core Voltage

Table 2-99 • 1.8 V LVCMOS Low Slew – Applies to 1.5 V DC Core Voltage

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 1.7 V

Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	$t_{ZL}$	$t_{ZH}$	$t_{LZ}$	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>ZHS</sub>	Units
2 mA	Std.	0.97	6.38	0.18	1.01	0.66	6.51	5.93	2.33	1.56	10.10	9.53	ns
4 mA	Std.	0.97	5.35	0.18	1.01	0.66	5.46	5.04	2.67	2.38	9.05	8.64	ns
6 mA	Std.	0.97	4.62	0.18	1.01	0.66	4.71	4.44	2.90	2.79	8.31	8.04	ns
8 mA	Std.	0.97	4.37	0.18	1.01	0.66	4.46	4.31	2.95	2.89	8.05	7.90	ns
12 mA	Std.	0.97	4.32	0.18	1.01	0.66	4.37	4.32	3.03	3.30	7.97	7.92	ns
16 mA	Std.	0.97	4.32	0.18	1.01	0.66	4.37	4.32	3.03	3.30	7.97	7.92	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

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### **B-LVDS/M-LVDS**

Bus LVDS (B-LVDS) and Multipoint LVDS (M-LVDS) specifications extend the existing LVDS standard to high-performance multipoint bus applications. Multidrop and multipoint bus configurations may contain any combination of drivers, receivers, and transceivers. Microsemi LVDS drivers provide the higher drive current required by B-LVDS and M-LVDS to accommodate the loading. The drivers require series terminations for better signal quality and to control voltage swing. Termination is also required at both ends of the bus since the driver can be located anywhere on the bus. These configurations can be implemented using the TRIBUF\_LVDS and BIBUF\_LVDS macros along with appropriate terminations. Multipoint designs using Microsemi LVDS macros can achieve up to 200 MHz with a maximum of 20 loads. A sample application is given in Figure 2-14. The input and output buffer delays are available in the LVDS section in Table 2-149 on page 2-81 and Table 2-150 on page 2-81.

Example: For a bus consisting of 20 equidistant loads, the following terminations provide the required differential voltage, in worst-case Industrial operating conditions, at the farthest receiver:  $R_S = 60~\Omega$  and  $R_T = 70~\Omega$ , given  $Z_0 = 50~\Omega$  (2") and  $Z_{stub} = 50~\Omega$  (~1.5").

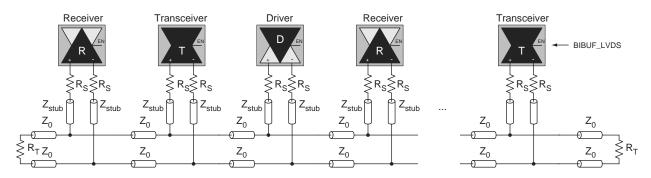


Figure 2-14 • B-LVDS/M-LVDS Multipoint Application Using LVDS I/O Buffers

### **LVPECL**

Low-Voltage Positive Emitter-Coupled Logic (LVPECL) is another differential I/O standard. It requires that one data bit be carried through two signal lines. Like LVDS, two pins are needed. It also requires external resistor termination.

The full implementation of the LVDS transmitter and receiver is shown in an example in Figure 2-15. The building blocks of the LVPECL transmitter-receiver are one transmitter macro, one receiver macro, three board resistors at the transmitter end, and one resistor at the receiver end. The values for the three driver resistors are different from those used in the LVDS implementation because the output standard specifications are different.

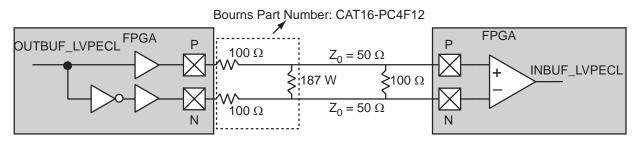


Figure 2-15 • LVPECL Circuit Diagram and Board-Level Implementation

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# I/O Register Specifications

# Fully Registered I/O Buffers with Synchronous Enable and Asynchronous Preset

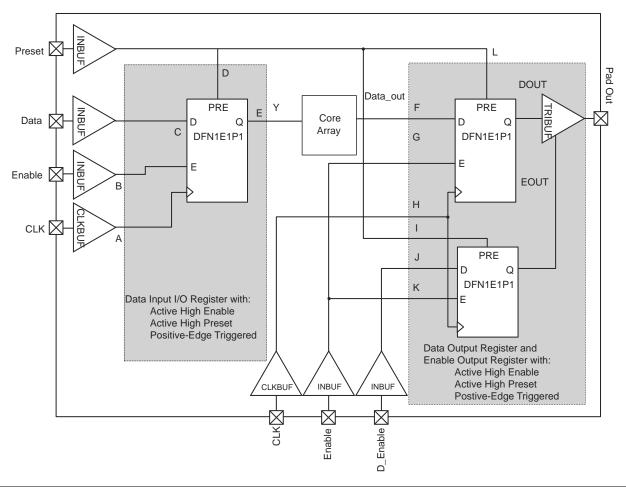


Figure 2-16 • Timing Model of Registered I/O Buffers with Synchronous Enable and Asynchronous Preset

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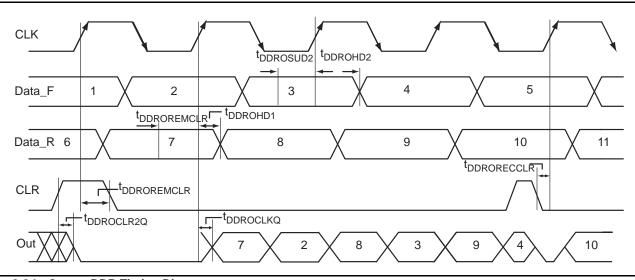


Figure 2-24 • Output DDR Timing Diagram

### **Timing Characteristics**

1.5 V DC Core Voltage

Table 2-167 • Output DDR Propagation Delays Commercial-Case Conditions:  $T_J = 70^{\circ}$ C, Worst-Case VCC = 1.425 V

Parameter	Description	Std.	Units
t <sub>DDROCLKQ</sub>	Clock-to-Out of DDR for Output DDR	1.07	ns
t <sub>DDROSUD1</sub>	Data_F Data Setup for Output DDR	0.67	ns
t <sub>DDROSUD2</sub>	Data_R Data Setup for Output DDR	0.67	ns
t <sub>DDROHD1</sub>	Data_F Data Hold for Output DDR	0.00	ns
t <sub>DDROHD2</sub>	Data_R Data Hold for Output DDR	0.00	ns
t <sub>DDROCLR2Q</sub>	Asynchronous Clear-to-Out for Output DDR	1.38	ns
t <sub>DDROREMCLR</sub>	Asynchronous Clear Removal Time for Output DDR	0.00	ns
t <sub>DDRORECCLR</sub>	Asynchronous Clear Recovery Time for Output DDR	0.23	ns
t <sub>DDROWCLR1</sub>	Asynchronous Clear Minimum Pulse Width for Output DDR	0.19	ns
t <sub>DDROCKMPWH</sub>	Clock Minimum Pulse Width High for the Output DDR	0.31	ns
t <sub>DDROCKMPWL</sub>	Clock Minimum Pulse Width Low for the Output DDR	0.28	ns
F <sub>DDOMAX</sub>	Maximum Frequency for the Output DDR	250.00	MHz

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

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## **Global Tree Timing Characteristics**

Global clock delays include the central rib delay, the spine delay, and the row delay. Delays do not include I/O input buffer clock delays, as these are I/O standard–dependent, and the clock may be driven and conditioned internally by the CCC module. For more details on clock conditioning capabilities, refer to the "Clock Conditioning Circuits" section on page 2-115. Table 2-173 to Table 2-188 on page 2-114 present minimum and maximum global clock delays within each device. Minimum and maximum delays are measured with minimum and maximum loading.

### **Timing Characteristics**

1.5 V DC Core Voltage

Table 2-173 • AGL015 Global Resource

Commercial-Case Conditions: T<sub>.I</sub> = 70°C, VCC = 1.425 V

		Std		
Parameter	Description	Min.	Max. <sup>2</sup>	Units
t <sub>RCKL</sub>	Input Low Delay for Global Clock	1.21	1.42	ns
t <sub>RCKH</sub>	Input High Delay for Global Clock	1.23	1.49	ns
t <sub>RCKMPWH</sub>	Minimum Pulse Width High for Global Clock	1.18		ns
t <sub>RCKMPWL</sub>	Minimum Pulse Width Low for Global Clock	1.15		ns
t <sub>RCKSW</sub>	Maximum Skew for Global Clock		0.27	ns

#### Notes:

- Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
- Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
- 3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

Table 2-174 • AGL030 Global Resource Commercial-Case Conditions: T<sub>J</sub> = 70°C, VCC = 1.425 V

			s		
Parameter	Description		Min. <sup>1</sup>	Max. <sup>2</sup>	Units
t <sub>RCKL</sub>	Input Low Delay for Global Clock		1.21	1.42	ns
t <sub>RCKH</sub>	Input High Delay for Global Clock		1.23	1.49	ns
t <sub>RCKMPWH</sub>	Minimum Pulse Width High for Global Clock		1.18		ns
t <sub>RCKMPWL</sub>	Minimum Pulse Width Low for Global Clock		1.15		ns
t <sub>RCKSW</sub>	Maximum Skew for Global Clock			0.27	ns

### Notes:

- 1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
- 2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
- 3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-7 for derating values.

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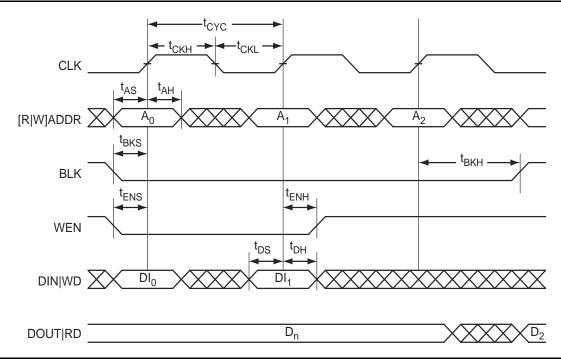


Figure 2-34 • RAM Write, Output Retained. Applicable to Both RAM4K9 and RAM512x18.

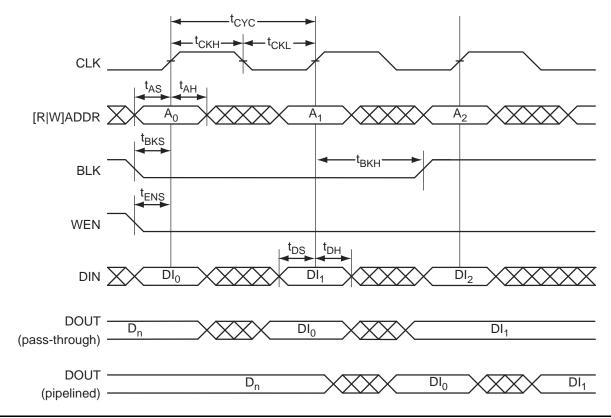


Figure 2-35 • RAM Write, Output as Write Data (WMODE = 1). Applicable to RAM4K9 only.

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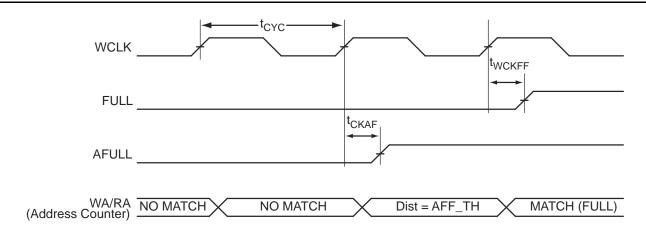


Figure 2-42 • FIFO FULL Flag and AFULL Flag Assertion

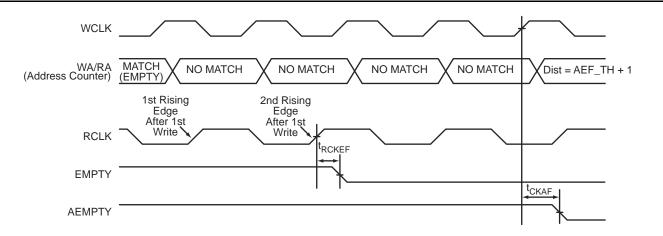


Figure 2-43 • FIFO EMPTY Flag and AEMPTY Flag Deassertion

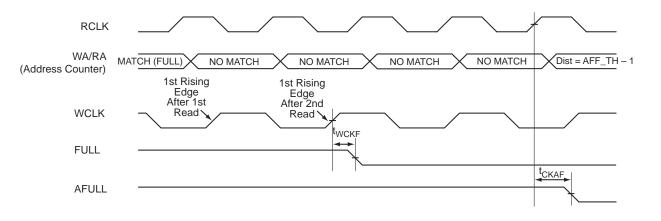


Figure 2-44 • FIFO FULL Flag and AFULL Flag Deassertion

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	CS196		CS196
Pin Number	AGL125 Function	Pin Number	AGL125 Function
A1	GND	C9	IO23RSB0
A2	GAA0/IO00RSB0	C10	IO29RSB0
А3	GAC0/IO04RSB0	C11	VCCIB0
A4	GAC1/IO05RSB0	C12	IO42RSB0
A5	IO09RSB0	C13	GNDQ
A6	IO15RSB0	C14	IO44RSB0
A7	IO18RSB0	D1	IO127RSB1
A8	IO22RSB0	D2	IO129RSB1
A9	IO27RSB0	D3	GAA2/IO132RSB1
A10	GBC0/IO35RSB0	D4	IO126RSB1
A11	GBB0/IO37RSB0	D5	IO06RSB0
A12	GBB1/IO38RSB0	D6	IO13RSB0
A13	GBA1/IO40RSB0	D7	IO19RSB0
A14	GND	D8	IO21RSB0
B1	VCCIB1	D9	IO26RSB0
B2	VMV0	D10	IO31RSB0
В3	GAA1/IO01RSB0	D11	IO30RSB0
B4	GAB1/IO03RSB0	D12	VMV0
B5	GND	D13	IO46RSB0
В6	IO16RSB0	D14	GBC2/IO45RSB0
B7	IO20RSB0	E1	IO125RSB1
B8	IO24RSB0	E2	GND
B9	IO28RSB0	E3	IO131RSB1
B10	GND	E4	VCCIB1
B11	GBC1/IO36RSB0	E5	NC
B12	GBA0/IO39RSB0	E6	IO08RSB0
B13	GBA2/IO41RSB0	E7	IO17RSB0
B14	GBB2/IO43RSB0	E8	IO12RSB0
C1	GAC2/IO128RSB1	E9	IO11RSB0
C2	GAB2/IO130RSB1	E10	NC
C3	GNDQ	E11	VCCIB0
C4	VCCIB0	E12	IO32RSB0
C5	GAB0/IO02RSB0	E13	GND
C6	IO14RSB0	E14	IO34RSB0
C7	VCCIB0	F1	IO124RSB1
C8	NC	F2	IO114RSB1

	CS196
Pin Number	AGL125 Function
F3	IO113RSB1
F4	IO112RSB1
F5	IO111RSB1
F6	NC
F7	VCC
F8	VCC
F9	NC
F10	IO07RSB0
F11	IO25RSB0
F12	IO10RSB0
F13	IO33RSB0
F14	IO47RSB0
G1	GFB1/IO121RSB1
G2	GFA0/IO119RSB1
G3	GFA2/IO117RSB1
G4	VCOMPLF
G5	GFC0/IO122RSB1
G6	VCC
<b>G</b> 7	GND
G8	GND
G9	VCC
G10	GCC0/IO52RSB0
G11	GCB1/IO53RSB0
G12	GCA0/IO56RSB0
G13	IO48RSB0
G14	GCC2/IO59RSB0
H1	GFB0/IO120RSB1
H2	GFA1/IO118RSB1
H3	VCCPLF
H4	GFB2/IO116RSB1
H5	GFC1/IO123RSB1
H6	VCC
H7	GND
H8	GND
H9	VCC
H10	GCC1/IO51RSB0

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QN132					
Pin Number	AGL060 Function				
C16	IO60RSB1				
C17	IO57RSB1				
C18	NC				
C19	TCK				
C20	VMV1				
C21	VPUMP				
C22	VJTAG				
C23	VCCIB0				
C24	NC				
C25	NC				
C26	GCA1/IO42RSB0				
C27	GCC0/IO39RSB0				
C28	VCCIB0				
C29	IO29RSB0				
C30	GNDQ				
C31	GBA1/IO27RSB0				
C32	GBB0/IO24RSB0				
C33	VCC				
C34	IO19RSB0				
C35	IO16RSB0				
C36	IO13RSB0				
C37	GAC1/IO10RSB0				
C38	NC				
C39	GAA0/IO05RSB0				
C40	VMV0				
D1	GND				
D2	GND				
D3	GND				
D4	GND				

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IGLOO Low Power Flash FPGAs

	FG144		FG144		FG144
Pin Number	AGL400 Function	Pin Number	AGL400 Function	Pin Number	AGL400 Function
A1	GNDQ	D1	IO149NDB3	G1	GFA1/IO145PPB3
A2	VMV0	D2	IO149PDB3	G2	GND
A3	GAB0/IO02RSB0	D3	IO153VDB3	G3	VCCPLF
A4	GAB1/IO03RSB0	D4	GAA2/IO155UPB3	G4	GFA0/IO145NPB3
A5	IO16RSB0	D5	GAC0/IO04RSB0	G5	GND
A6	GND	D6	GAC1/IO05RSB0	G6	GND
A7	IO30RSB0	D7	GBC0/IO54RSB0	G7	GND
A8	VCC	D8	GBC1/IO55RSB0	G8	GDC1/IO77UPB1
A9	IO34RSB0	D9	GBB2/IO61PDB1	G9	IO72NDB1
A10	GBA0/IO58RSB0	D10	IO61NDB1	G10	GCC2/IO72PDB1
A11	GBA1/IO59RSB0	D11	IO62NPB1	G11	IO71NDB1
A12	GNDQ	D12	GCB1/IO68PPB1	G12	GCB2/IO71PDB1
B1	GAB2/IO154UDB3	E1	VCC	H1	VCC
B2	GND	E2	GFC0/IO147NDB3	H2	GFB2/IO143PDB3
В3	GAA0/IO00RSB0	E3	GFC1/IO147PDB3	H3	GFC2/IO142PSB3
B4	GAA1/IO01RSB0	E4	VCCIB3	H4	GEC1/IO137PDB3
B5	IO14RSB0	E5	IO155VPB3	H5	VCC
В6	IO19RSB0	E6	VCCIB0	H6	IO75PDB1
B7	IO23RSB0	E7	VCCIB0	H7	IO75NDB1
B8	IO31RSB0	E8	GCC1/IO67PDB1	H8	GDB2/IO81RSB2
В9	GBB0/IO56RSB0	E9	VCCIB1	H9	GDC0/IO77VPB1
B10	GBB1/IO57RSB0	E10	VCC	H10	VCCIB1
B11	GND	E11	GCA0/IO69NDB1	H11	IO73PSB1
B12	VMV1	E12	IO70NDB1	H12	VCC
C1	IO154VDB3	F1	GFB0/IO146NPB3	J1	GEB1/IO136PDB3
C2	GFA2/IO144PPB3	F2	VCOMPLF	J2	IO143NDB3
C3	GAC2/IO153UDB3	F3	GFB1/IO146PPB3	J3	VCCIB3
C4	VCC	F4	IO144NPB3	J4	GEC0/IO137NDB3
C5	IO12RSB0	F5	GND	J5	IO125RSB2
C6	IO17RSB0	F6	GND	J6	IO116RSB2
C7	IO25RSB0	F7	GND	J7	VCC
C8	IO32RSB0	F8	GCC0/IO67NDB1	J8	TCK
C9	IO53RSB0	F9	GCB0/IO68NPB1	J9	GDA2/IO80RSB2
C10	GBA2/IO60PDB1	F10	GND	J10	TDO
C11	IO60NDB1	F11	GCA1/IO69PDB1	J11	GDA1/IO79UDB1
C12	GBC2/IO62PPB1	F12	GCA2/IO70PDB1	J12	GDB1/IO78UDB1

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FG256	
Pin Number	AGL1000 Function
A1	GND
A2	GAA0/IO00RSB0
A3	GAA1/IO01RSB0
A4	GAB0/IO02RSB0
A5	IO16RSB0
A6	IO22RSB0
A7	IO28RSB0
A8	IO35RSB0
A9	IO45RSB0
A10	IO50RSB0
A11	IO55RSB0
A12	IO61RSB0
A13	GBB1/IO75RSB0
A14	GBA0/IO76RSB0
A15	GBA1/IO77RSB0
A16	GND
B1	GAB2/IO224PDB3
B2	GAA2/IO225PDB3
В3	GNDQ
B4	GAB1/IO03RSB0
B5	IO17RSB0
В6	IO21RSB0
B7	IO27RSB0
B8	IO34RSB0
В9	IO44RSB0
B10	IO51RSB0
B11	IO57RSB0
B12	GBC1/IO73RSB0
B13	GBB0/IO74RSB0
B14	IO71RSB0
B15	GBA2/IO78PDB1
B16	IO81PDB1
C1	IO224NDB3
C2	IO225NDB3
C3	VMV3
C4	IO11RSB0
C5	GAC0/IO04RSB0
C6	GAC1/IO05RSB0

FG256	
Pin Number	AGL1000 Function
C7	IO25RSB0
C8	IO36RSB0
C9	IO42RSB0
C10	IO49RSB0
C11	IO56RSB0
C12	GBC0/IO72RSB0
C13	IO62RSB0
C14	VMV0
C15	IO78NDB1
C16	IO81NDB1
D1	IO222NDB3
D2	IO222PDB3
D3	GAC2/IO223PDB3
D4	IO223NDB3
D5	GNDQ
D6	IO23RSB0
D7	IO29RSB0
D8	IO33RSB0
D9	IO46RSB0
D10	IO52RSB0
D11	IO60RSB0
D12	GNDQ
D13	IO80NDB1
D14	GBB2/IO79PDB1
D15	IO79NDB1
D16	IO82NSB1
E1	IO217PDB3
E2	IO218PDB3
E3	IO221NDB3
E4	IO221PDB3
E5	VMV0
E6	VCCIB0
E7	VCCIB0
E8	IO38RSB0
E9	IO47RSB0
E10	VCCIB0
E11	VCCIB0
E12	VMV1

FG256	
Pin Number	AGL1000 Function
E13	GBC2/IO80PDB1
E14	IO83PPB1
E15	IO86PPB1
E16	IO87PDB1
F1	IO217NDB3
F2	IO218NDB3
F3	IO216PDB3
F4	IO216NDB3
F5	VCCIB3
F6	GND
F7	VCC
F8	VCC
F9	VCC
F10	VCC
F11	GND
F12	VCCIB1
F13	IO83NPB1
F14	IO86NPB1
F15	IO90PPB1
F16	IO87NDB1
G1	IO210PSB3
G2	IO213NDB3
G3	IO213PDB3
G4	GFC1/IO209PPB3
G5	VCCIB3
G6	VCC
G7	GND
G8	GND
G9	GND
G10	GND
G11	VCC
G12	VCCIB1
G13	GCC1/IO91PPB1
G14	IO90NPB1
G15	IO88PDB1
G16	IO88NDB1
H1	GFB0/IO208NPB3
H2	GFA0/IO207NDB3

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	FG256
Pin Number	AGL1000 Function
R5	IO168RSB2
R6	IO163RSB2
R7	IO157RSB2
R8	IO149RSB2
R9	IO143RSB2
R10	IO138RSB2
R11	IO131RSB2
R12	IO125RSB2
R13	GDB2/IO115RSB2
R14	TDI
R15	GNDQ
R16	TDO
T1	GND
T2	IO183RSB2
Т3	FF/GEB2/IO186RSB2
T4	IO172RSB2
T5	IO170RSB2
T6	IO164RSB2
T7	IO158RSB2
Т8	IO153RSB2
Т9	IO142RSB2
T10	IO135RSB2
T11	IO130RSB2
T12	GDC2/IO116RSB2
T13	IO120RSB2
T14	GDA2/IO114RSB2
T15	TMS
T16	GND

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	FG484
Pin Number	AGL400 Function
C21	NC
C22	VCCIB1
D1	NC
D2	NC
D3	NC
D4	GND
D5	GAA0/IO00RSB0
D6	GAA1/IO01RSB0
D7	GAB0/IO02RSB0
D8	IO16RSB0
D9	IO17RSB0
D10	IO22RSB0
D11	IO28RSB0
D12	IO34RSB0
D13	IO37RSB0
D14	IO41RSB0
D15	IO43RSB0
D16	GBB1/IO57RSB0
D17	GBA0/IO58RSB0
D18	GBA1/IO59RSB0
D19	GND
D20	NC
D21	NC
D22	NC
E1	NC
E2	NC
E3	GND
E4	GAB2/IO154UDB3
E5	GAA2/IO155UDB3
E6	IO12RSB0
E7	GAB1/IO03RSB0
E8	IO13RSB0
E9	IO14RSB0
E10	IO21RSB0
E11	IO27RSB0
E12	IO32RSB0

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FG484	
Pin Number	AGL400 Function
V15	IO85RSB2
V16	GDB2/IO81RSB2
V17	TDI
V18	NC
V19	TDO
V20	GND
V21	NC
V22	NC
W1	NC
W2	NC
W3	NC
W4	GND
W5	IO126RSB2
W6	FF/GEB2/IO133RSB2
W7	IO124RSB2
W8	IO116RSB2
W9	IO113RSB2
W10	IO107RSB2
W11	IO105RSB2
W12	IO102RSB2
W13	IO97RSB2
W14	IO92RSB2
W15	GDC2/IO82RSB2
W16	IO86RSB2
W17	GDA2/IO80RSB2
W18	TMS
W19	GND
W20	NC
W21	NC
W22	NC
Y1	VCCIB3
Y2	NC
Y3	NC
Y4	NC
Y5	GND
Y6	NC

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	FG484
D' N . I	
Pin Number	AGL1000 Function
V15	IO125RSB2
V16	GDB2/IO115RSB2
V17	TDI
V18	GNDQ
V19	TDO
V20	GND
V21	NC
V22	IO109NDB1
W1	NC
W2	IO191PDB3
W3	NC
W4	GND
W5	IO183RSB2
W6	FF/GEB2/IO186RSB2
W7	IO172RSB2
W8	IO170RSB2
W9	IO164RSB2
W10	IO158RSB2
W11	IO153RSB2
W12	IO142RSB2
W13	IO135RSB2
W14	IO130RSB2
W15	GDC2/IO116RSB2
W16	IO120RSB2
W17	GDA2/IO114RSB2
W18	TMS
W19	GND
W20	NC
W21	NC
W22	NC
Y1	VCCIB3
Y2	IO191NDB3
Y3	NC
Y4	IO182RSB2
Y5	GND
Y6	IO177RSB2
	<u> </u>

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IGLOO Low Power Flash FPGAs

Revision	Changes	Page
Revision 19	The following sentence was removed from the "Advanced Architecture" section:	1-3
(continued)	"In addition, extensive on-chip programming circuitry allows for rapid, single-voltage (3.3 V) programming of IGLOO devices via an IEEE 1532 JTAG interface" (SAR 28756).	
	The "Specifying I/O States During Programming" section is new (SAR 21281).	1-8
	Values for VCCPLL at 1.2 V −1.5 V DC core supply voltage were revised in Table 2-2 • Recommended Operating Conditions 1 (SAR 22356).	2-2
	The value for VPUMP operation was changed from "0 to 3.45 V" to "0 to 3.6 V" (SAR 25220).	
	The value for VCCPLL 1.5 V DC core supply voltage was changed from "1.4 to 1.6 V" to "1.425 to 1.575 V" (SAR 26551).	
	The notes in the table were renumbered in order of their appearance in the table (SAR 21869).	
	The temperature used in EQ 2 was revised from 110°C to 100°C for consistency with the limits given in Table 2-2 • Recommended Operating Conditions 1. The resulting maximum power allowed is thus 1.28 W. Formerly it was 1.71 W (SAR 26259).	2-6
	Values for CS196, CS281, and QN132 packages were added to Table 2-5 • Package Thermal Resistivities (SARs 26228, 32301).	2-6
	Table 2-6 • Temperature and Voltage Derating Factors for Timing Delays (normalized to TJ = $70^{\circ}$ C, VCC = $1.425$ V) and Table 2-7 • Temperature and Voltage Derating Factors for Timing Delays (normalized to TJ = $70^{\circ}$ C, VCC = $1.14$ V) were updated to remove the column for $-20^{\circ}$ C and shift the data over to correct columns (SAR 23041).	2-7
	The tables in the "Quiescent Supply Current" section were updated with revised notes on IDD (SAR 24112). Table 2-8 • Power Supply State per Mode is new.	2-7
	The formulas in the table notes for Table 2-41 • I/O Weak Pull-Up/Pull-Down Resistances were corrected (SAR 21348).	2-37
	The row for 110°C was removed from Table 2-45 • Duration of Short Circuit Event before Failure. The example in the associated paragraph was changed from 110°C to 100°C. Table 2-46 • I/O Input Rise Time, Fall Time, and Related I/O Reliability1 was revised to change 110° to 100°C. (SAR 26259).	2-40
	The notes regarding drive strength in the "Summary of I/O Timing Characteristics -	2-28,
	Default I/O Software Settings" section, "3.3 V LVCMOS Wide Range" section and "1.2 V LVCMOS Wide Range" section tables were revised for clarification. They now state that the minimum drive strength for the default software configuration when run in wide range is $\pm 100~\mu A$ . The drive strength displayed in software is supported in normal range only. For a detailed I/V curve, refer to the IBIS models (SAR 25700).	2-47, 2-77
	The following sentence was deleted from the "2.5 V LVCMOS" section (SAR 24916): "It uses a 5 V-tolerant input buffer and push-pull output buffer."	2-56
	The values for $F_{DDRIMAX}$ and $F_{DDOMAX}$ were updated in the tables in the "Input DDR Module" section and "Output DDR Module" section (SAR 23919).	2-94, 2-97
	The following notes were removed from Table 2-147 • Minimum and Maximum DC Input and Output Levels (SAR 29428): ±5%	2-81
	Differential input voltage = ±350 mV	
	Table 2-189 • IGLOO CCC/PLL Specification and Table 2-190 • IGLOO CCC/PLL Specification were updated. A note was added to both tables indicating that when the CCC/PLL core is generated by Mircosemi core generator software, not all delay values of the specified delay increments are available (SAR 25705).	2-115

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### Datasheet Information

Revision	Changes	Page
Revision 19	The following figures were deleted (SAR 29991). Reference was made to a new application note, Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs, which covers these cases in detail (SAR 21770).	
	Figure 2-36 • Write Access after Write onto Same Address	
	Figure 2-37 • Read Access after Write onto Same Address	
	Figure 2-38 • Write Access after Read onto Same Address	2-119 to
	The port names in the SRAM "Timing Waveforms", SRAM "Timing Characteristics" tables, Figure 2-40 • FIFO Reset, and the FIFO "Timing Characteristics" tables were revised to ensure consistency with the software names (SARs 29991, 30510).	2-130
	The "Pin Descriptions" chapter has been added (SAR 21642).	3-1
	Package names used in the "Package Pin Assignments" section were revised to match standards given in <i>Package Mechanical Drawings</i> (SAR 27395).	4-1
	The "CS81" pin table for AGL250 is new (SAR 22737).	4-5
	The CS121 pin table for AGL125 is new (SAR 22737).	
	The P3 function was revised in the "CS196" pin table for AGL250 (SAR 24800).	4-12
	The "QN132" pin table for AGL250 was added.	4-35,
	The "FG144" pin table for AGL060 was added (SAR 33689)	4-42
July 2010	The versioning system for datasheets has been changed. Datasheets are assigned a revision number that increments each time the datasheet is revised. The "IGLOO Device Status" table indicates the status for each device in the device family.	N/A

5-5 Revision 27



IGLOO Low Power Flash FPGAs

Revision / Version	Changes	Page
DC & Switching, cont'd.	Table 2-49 · Minimum and Maximum DC Input and Output Levels for LVCMOS 3.3 V Wide Range is new.	2-39
Revision 9 (Jul 2008) Product Brief v1.1 DC and Switching Characteristics Advance v0.3	As a result of the Libero IDE v8.4 release, Actel now offers a wide range of core voltage support. The document was updated to change 1.2 V / 1.5 V to 1.2 V to 1.5 V.	N/A
Revision 8 (Jun 2008)	As a result of the Libero IDE v8.4 release, Actel now offers a wide range of core voltage support. The document was updated to change 1.2 V / 1.5 V to 1.5 V.	N/A
DC and Switching Characteristics Advance v0.2	Tables have been updated to reflect default values in the software. The default I/O capacitance is 5 pF. Tables have been updated to include the LVCMOS 1.2 V I/O set.  DDR Tables have two additional data points added to reflect both edges for Input DDR setup and hold time.  The power data table has been updated to match SmartPower data rather then simulation values.	N/A
	AGL015 global clock delays have been added.	
	Table 2-1 • Absolute Maximum Ratings was updated to combine the VCCI and VMV parameters in one row. The word "output" from the parameter description for VCCI and VMV, and table note 3 was added.	2-1
	Table 2-2 • Recommended Operating Conditions 1 was updated to add references to tables notes 4, 6, 7, and 8. VMV was added to the VCCI parameter row, and table note 9 was added.	2-2
	In Table 2-3 • Flash Programming Limits – Retention, Storage, and Operating Temperature1, the maximum operating junction temperature was changed from 110° to 100°.	2-3
	VMV was removed from Table 2-4 • Overshoot and Undershoot Limits 1. The table title was modified to remove "as measured on quiet I/Os." Table note 2 was revised to remove "estimated SSO density over cycles." Table note 3 was revised to remove "refers only to overshoot/undershoot limits for simultaneous switching I/Os."	2-3
	The "PLL Behavior at Brownout Condition" section is new.	2-4
	Figure 2-2 • V2 Devices – I/O State as a Function of VCCI and VCC Voltage Levels is new.	2-5
	EQ 2 was updated. The temperature was changed to 100°C, and therefore the end result changed.	2-6
	The table notes for Table 2-9 • Quiescent Supply Current (IDD) Characteristics, IGLOO Flash*Freeze Mode*, Table 2-10 • Quiescent Supply Current (IDD) Characteristics, IGLOO Sleep Mode*, and Table 2-11 • Quiescent Supply Current (IDD) Characteristics, IGLOO Shutdown Mode were updated to remove VMV and include PDC6 and PDC7. VCCI and VJTAG were removed from the statement about IDD in the table note for Table 2-11 • Quiescent Supply Current (IDD) Characteristics, IGLOO Shutdown Mode.	2-7
	Note 2 of Table 2-12 • Quiescent Supply Current (IDD), No IGLOO Flash*Freeze Mode1 was updated to include VCCPLL. Note 4 was updated to include PDC6 and PDC7.	2-9

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